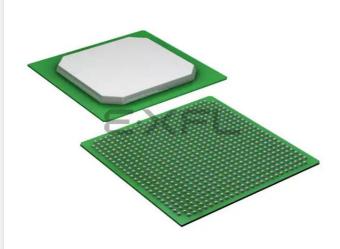
Intel - EP4CGX110DF27I7 Datasheet





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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Details	
Product Status	Active
Number of LABs/CLBs	6839
Number of Logic Elements/Cells	109424
Total RAM Bits	5621760
Number of I/O	393
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx110df27i7

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Cyclone IV E industrial devices I7 are offered with extended operating temperature range.

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Cyclone IV devices. The values are based on experiments conducted with the device and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied at these conditions. Table 1–1 lists the absolute maximum ratings for Cyclone IV devices.



Conditions beyond those listed in Table 1–1 cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time have adverse effects on the device.

Symbol	Parameter	Min	Max	Unit
V _{CCINT}	Core voltage, PCI Express [®] (PCIe [®]) hard IP block, and transceiver physical coding sublayer (PCS) power supply	-0.5	1.8	V
V _{CCA}	Phase-locked loop (PLL) analog power supply	-0.5	3.75	V
V _{CCD_PLL}	PLL digital power supply	-0.5	1.8	V
V _{CCIO}	I/O banks power supply	-0.5	3.75	V
V _{CC_CLKIN}	Differential clock input pins power supply	-0.5	4.5	V
V _{CCH_GXB}	Transceiver output buffer power supply	-0.5	3.75	V
V _{CCA_GXB}	Transceiver physical medium attachment (PMA) and auxiliary power supply	-0.5	3.75	V
V _{CCL_GXB}	Transceiver PMA and auxiliary power supply	-0.5	1.8	V
VI	DC input voltage	-0.5	4.2	V
I _{OUT}	DC output current, per pin	-25	40	mA
T _{STG}	Storage temperature	-65	150	°C
TJ	Operating junction temperature	-40	125	°C

Table 1–1. Absolute Maximum Ratings for Cyclone IV Devices (1)

Note to Table 1–1:

(1) Supply voltage specifications apply to voltage readings taken at the device pins with respect to ground, not at the power supply.

Maximum Allowed Overshoot or Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in Table 1–2 and undershoot to –2.0 V for a magnitude of currents less than 100 mA and for periods shorter than 20 ns. Table 1–2 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage over the lifetime of the device. The maximum allowed overshoot duration is specified as a percentage of high-time over the lifetime of the device.

Table 1-3.	Recommended Operating Conditions for Cyclone IV E Devices ^{(1), (2}	⁹ (Part 2 of 2)
------------	--	----------------------------

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I _{Diode}	Magnitude of DC current across PCI-clamp diode when enable	_	_		10	mA

Notes to Table 1–3:

 Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades.

(2) V_{CCI0} for all I/O banks must be powered up during device operation. All vCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(3) V_{CC} must rise monotonically.

(4) V_{CCI0} powers all input buffers.

(5) The POR time for Standard POR ranges between 50 and 200 ms. Each individual power supply must reach the recommended operating range within 50 ms.

(6) The POR time for Fast POR ranges between 3 and 9 ms. Each individual power supply must reach the recommended operating range within 3 ms.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{ccint} <i>(3)</i>	Core voltage, PCIe hard IP block, and transceiver PCS power supply		1.16	1.2	1.24	V
V _{CCA} (1), (3)	PLL analog power supply	_	2.375	2.5	2.625	V
V _{CCD_PLL} <i>(2)</i>	PLL digital power supply	_	1.16	1.2	1.24	V
	I/O banks power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	I/O banks power supply for 3.0-V operation	—	2.85	3	3.15	V
V _{ccio} <i>(3), (4)</i>	I/O banks power supply for 2.5-V operation	_	2.375	2.5	2.625	V
VCCIO (S), (S)	I/O banks power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	I/O banks power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	I/O banks power supply for 1.2-V operation	_	1.14	1.2	1.26	V
	Differential clock input pins power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	Differential clock input pins power supply for 3.0-V operation	—	2.85	3	3.15	V
V _{CC_CLKIN}	Differential clock input pins power supply for 2.5-V operation	—	2.375	2.5	2.625	V
(3), (5), (6)	Differential clock input pins power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	Differential clock input pins power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	Differential clock input pins power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V _{CCH_GXB}	Transceiver output buffer power supply	_	2.375	2.5	2.625	V

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 1 of 2)

			V _{CCIO} (V)											
Parameter	Condition	1	.2	1	.5	1	.8	2	.5	3	.0	3	.3	Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2)⁽¹⁾

Note to Table 1-7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

		Resistance	e Tolerance	
Description	V _{CCIO} (V)	Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	Unit
	3.0	±30	±40	%
	2.5	±30	±40	%
Series OCT without calibration	1.8	±40	±50	%
	1.5	±50	±50	%
	1.2	±50	±50	%

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

		Calibratio	n Accuracy	
Description	V _{CCIO} (V)	Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	Unit
	3.0	±10	±10	%
Series OCT with	2.5	±10	±10	%
calibration at device	1.8	±10	±10	%
power-up	1.5	±10	±10	%
	1.2	±10	±10	%

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1–12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1–12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (2), (3)	7	25	41	kΩ
	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the	$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (2), (3)	7	28	47	kΩ
R		$V_{CCIO} = 2.5 \text{ V} \pm 5\%$ (2), (3)	8	35	61	kΩ
IN_PU		$V_{CCIO} = 1.8 \text{ V} \pm 5\%$ (2), (3)	10	57	108	kΩ
	programmable pull-up resistor option	$V_{CCIO} = 1.5 \text{ V} \pm 5\%$ (2), (3)	13	82	163	kΩ
		$V_{CCIO} = 1.2 \text{ V} \pm 5\%$ (2), (3)	19	143	351	kΩ
		$V_{CCIO} = 3.3 \text{ V} \pm 5\%$ (4)	6	19	30	kΩ
	Value of the I/O pin pull-down resistor before and during configuration	$V_{CCIO} = 3.0 \text{ V} \pm 5\%$ (4)	6	22	36	kΩ
R_ _{PD}		$V_{CCIO} = 2.5 V \pm 5\%$ (4)	6	25	43	kΩ
		$V_{CCIO} = 1.8 V \pm 5\%$ (4)	7	35	71	kΩ
		$V_{CCIO} = 1.5 V \pm 5\%$ (4)	8	50	112	kΩ

Notes to Table 1–12:

- (1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO} .
- $\begin{array}{ll} \text{(3)} & \text{R}_{_{PU}} = (\text{V}_{\text{CCI0}} \text{V}_{\text{I}})/\text{I}_{\text{R}_{_{PU}}} \\ & \text{Minimum condition: } -40^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} + 5\%, \ \text{V}_{\text{I}} = \text{V}_{\text{CC}} + 5\% 50 \ \text{mV}; \\ & \text{Typical condition: } 25^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}}, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CCI0}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CC}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = \text{V}_{\text{CO}} 5\%, \ \text{V}_{\text{I}} = 0 \ \text{V}; \\ & \text{Maximum condition: } 100^{\circ}\text{C}; \ \text{V}_{\text{CO}} = 10^{\circ}\text{C}; \ \text{V}_{\text{CO}} = 10^{\circ$
- $\begin{array}{ll} (4) & R_{_PD} = V_I/I_{R_PD} \\ & \text{Minimum condition:} -40^{\circ}\text{C}; \ V_{CCIO} = V_{CC} + 5\%, \ V_I = 50 \ \text{mV}; \\ & \text{Typical condition:} \ 25^{\circ}\text{C}; \ V_{CCIO} = V_{CC}, \ V_I = V_{CC} 5\%; \\ & \text{Maximum condition:} \ 100^{\circ}\text{C}; \ V_{CCIO} = V_{CC} 5\%, \ V_I = V_{CC} 5\%; \ \text{in which } V_I \ \text{refers to the input voltage at the I/O pin.} \end{array}$

Hot-Socketing

Table 1–13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1–13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Symbol Parameter				
I _{IOPIN(DC)}	DC current per I/O pin	300 μA			
I _{IOPIN(AC)}	AC current per I/O pin	8 mA <i>(1)</i>			
I _{XCVRTX(DC)}	DC current per transceiver TX pin	100 mA			
I _{XCVRRX(DC)}	DC current per transceiver RX pin	50 mA			

Note to Table 1-13:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |IIOPIN| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

I/O		V _{ccio} (V))		V _{REF} (V)		V _{TT} (V) <i>(2)</i>			
Standard	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
SSTL-2 Class I, II	2.375	2.5	2.625	1.19	1.25	1.31	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04	
SSTL-18 Class I, II	1.7	1.8	1.9	0.833	0.9	0.969	V _{REF} – 0.04	V _{REF}	V _{REF} + 0.04	
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	0.85	0.9	0.95	
HSTL-15 Class I, II	1.425	1.5	1.575	0.71	0.75	0.79	0.71	0.75	0.79	
HSTL-12 Class I, II	1.14	1.2	1.26	0.48 x V _{CCI0} (3) 0.47 x V _{CCI0} (4)	$\begin{array}{c} 0.5 \mbox{ x } V_{\rm CC10} \ \ {}^{(3)} \\ 0.5 \mbox{ x } V_{\rm CC10} \ \ {}^{(4)} \end{array}$	$\begin{array}{l} 0.52 \times V_{\rm CCI0} \ {}^{(3)} \\ 0.53 \times V_{\rm CCI0} \ {}^{(4)} \end{array}$	_	0.5 x V _{CCIO}	_	

Notes to Table 1–16:

(1) For an explanation of terms used in Table 1–16, refer to "Glossary" on page 1–37.

(2) $~V_{TT}$ of the transmitting device must track V_{REF} of the receiving device.

(3) Value shown refers to DC input reference voltage, $V_{\text{REF(DC)}}.$

(4) Value shown refers to AC input reference voltage, $V_{\text{REF(AC)}}$.

Table 1-17.	Single-Ended SSTL and HST	L I/O Standards Signal S	Specifications for C	yclone IV Devices
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I/O	V _{IL(}	_(DC) (V)	VIII	_{I(DC)} (V)	V _{IL(}	_{AC)} (V)	VIH	_(AC) (V)	V _{OL} (V)	V _{oh} (V)	I _{OL}	I _{oh}
Standard	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min	(mĀ)	(mÄ)
SSTL-2 Class I		V _{REF} – 0.18	V _{REF} + 0.18	_		V _{REF} – 0.35	V _{REF} + 0.35	—	V _{ττ} – 0.57	V _{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	_	V _{REF} – 0.18	V _{REF} + 0.18	—	_	V _{REF} – 0.35	V _{REF} + 0.35	—	V _{TT} – 0.76	V _{TT} + 0.76	16.4	-16.4
SSTL-18 Class I	_	V _{REF} – 0.125	V _{REF} + 0.125	—	_	V _{REF} – 0.25	V _{REF} + 0.25	—	V _{TT} – 0.475	V _{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	_	V _{REF} – 0.125	V _{REF} + 0.125	_	_	V _{REF} – 0.25	V _{REF} + 0.25	—	0.28	V _{CCI0} – 0.28	13.4	-13.4
HSTL-18 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCI0} – 0.4	8	-8
HSTL-18 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCI0} – 0.4	16	-16
HSTL-15 Class I	_	V _{REF} – 0.1	V _{REF} + 0.1	—	_	V _{REF} – 0.2	V _{REF} + 0.2	—	0.4	V _{CCIO} – 0.4	8	-8
HSTL-15 Class II	_	V _{REF} – 0.1	V _{REF} + 0.1	_	_	V _{REF} – 0.2	V _{REF} + 0.2	_	0.4	V _{CCI0} – 0.4	16	-16
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCI0} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCI0} + 0.24	0.25 × V _{CCI0}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} – 0.08	V _{REF} + 0.08	V _{CCI0} + 0.15	-0.24	V _{REF} – 0.15	V _{REF} + 0.15	V _{CCI0} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14

• For more information about receiver input and transmitter output waveforms, and for other differential I/O standards, refer to the *I/O Features in Cyclone IV Devices* chapter.

Table 1–18. Differential SSTL I/O Standard Specifications for Cyclone IV Devices (1)

I/O Standard	Standard)	V _{Swing(DC)} (V)		V _{X(AC)} (V)			V _{Swing(AC)} (V)		V _{OX(AC)} (V)		
	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Max	Min	Тур	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V _{CCIO}	$V_{CCIO}/2 - 0.2$	_	V _{CCI0} /2 + 0.2	0.7	V _{CCI} 0	V _{CCIO} /2 – 0.125		V _{CCI0} /2 + 0.125
SSTL-18 Class I, II	1.7	1.8	1.90	0.25	V _{CCIO}	V _{CCIO} /2 – 0.175	_	V _{CCI0} /2 + 0.175	0.5	V _{CCI} 0	V _{CCIO} /2 – 0.125	_	V _{CCI0} /2 + 0.125

Note to Table 1–18:

(1) Differential SSTL requires a V_{REF} input.

Table 1–19. Differential HSTL I/O Standard Specifications for Cyclone IV Devices ⁽¹⁾

	V _{CCIO} (V)		V _{DIF(DC)} (V)		Vx	V _{X(AC)} (V)		V _{CM(DC)} (V)			V _{DIF(AC)} (V)		
I/O Standard	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Mi n	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	_	0.85	—	0.95	0.85	—	0.95	0.4	_
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	_	0.71	_	0.79	0.71	_	0.79	0.4	_
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCIO}	$0.48 \times V_{CCIO}$	_	0.52 x V _{CCI0}	0.48 x V _{CCIO}	_	0.52 x V _{CCI0}	0.3	0.48 x V _{CCI0}

Note to Table 1-19:

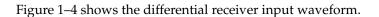
(1) Differential HSTL requires a V_{REF} input.

 Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices ⁽¹⁾ (Part 1 of 2)

I/O Standard		V _{CCIO} (V)		V _{ID} (mV)		V _{ICM} (V) ⁽²⁾	V _{ICM} (V) ⁽²⁾ V		V _{oD} (mV) ⁽³⁾		V _{0S} (V) ⁽³⁾			
i/U Stalluaru	Min	Тур	Max	Min	Max Mi		Condition	Max	Min	Тур	Max	Min	Тур	Max
						0.05	$D_{MAX} \leq 500 \; Mbps$	1.80						
LVPECL (Row I/Os) (6)	2.375	2.5	2.625	100	_	0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{ D}_{\text{MAX}} \\ \leq 700 \text{ Mbps} \end{array}$	1.80	_	—	_	—	—	_
						1.05	D _{MAX} > 700 Mbps	1.55						
						0.05	$D_{MAX} \leq ~500~Mbps$	1.80						
LVPECL (Column I/Os) <i>(6)</i>	2.375	2.5	2.625	100		0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{D}_{\text{MAX}} \\ \leq 700 \text{ Mbps} \end{array}$	1.80	_	—	_	_	_	_
1/03/						1.05	D _{MAX} > 700 Mbps	1.55						
						0.05	$D_{MAX} \leq 500 \; Mbps$	1.80						
LVDS (Row I/Os)	2.375	2.5	2.625	100	_	0.55	$\begin{array}{l} 500 \text{ Mbps} \leq \text{D}_{\text{MAX}} \\ \leq \ 700 \text{ Mbps} \end{array}$	1.80	247	—	600	1.125	1.25	1.375
						1.05	D _{MAX} > 700 Mbps	1.55						

Symbol/	0		C6			C7, I7			C 8		
Description	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Signal detect/loss threshold	PIPE mode	65	_	175	65	_	175	65	_	175	mV
t _{LTR} (10)	_			75			75			75	μs
t _{LTR-LTD_Manual} (11)	—	15	_	_	15	—	—	15	_	—	μs
t _{LTD} (12)	—	0	100	4000	0	100	4000	0	100	4000	ns
t _{LTD_Manual} (13)	—			4000	—	—	4000			4000	ns
t _{LTD_Auto} (14)		_		4000	_	_	4000	_		4000	ns
Receiver buffer and CDR offset cancellation time (per channel)	_			17000	_	_	17000		_	17000	recon fig_c lk cycles
	DC Gain Setting = 0	_	0		_	0	_	_	0	_	dB
Programmable DC gain	DC Gain Setting = 1	_	3	_	_	3	_		3	_	dB
	DC Gain Setting = 2	_	6	_	_	6	_		6	_	dB
Transmitter											
Supported I/O Standards	1.5 V PCML										
Data rate (F324 and smaller package)	_	600	_	2500	600	_	2500	600	_	2500	Mbps
Data rate (F484 and larger package)	_	600	_	3125	600	_	3125	600	_	2500	Mbps
V _{OCM}	0.65 V setting		650	—	—	650	—	_	650	—	mV
Differential on-chip	100– Ω setting		100		—	100	—	_	100	—	Ω
termination resistors	150– Ω setting		150	_	—	150	—		150	—	Ω
Differential and common mode return loss	PIPE, CPRI LV, Serial Rapid I/O SR, SDI, XAUI, SATA				·	Complian	t				_
Rise time		50		200	50		200	50		200	ps
Fall time	—	50		200	50	—	200	50	_	200	ps
Intra-differential pair skew	—	_	_	15	-	-	15	_	_	15	ps
Intra-transceiver block skew	—		_	120	-	_	120	_	_	120	ps

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 3 of 4)





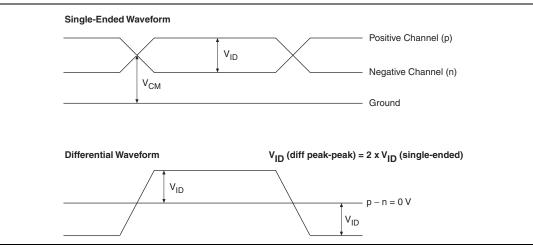


Figure 1–5 shows the transmitter output waveform.



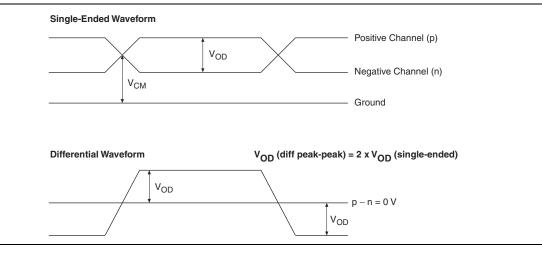


Table 1–22 lists the typical V_{OD} for Tx term that equals 100 Ω .

Table 1–22. Typical V_{0D} Setting, Tx Term = 100 Ω

Symbol	V _{oD} Setting (mV)									
Symbol	1	2	3	4 (1)	5	6				
V _{OD} differential peak to peak typical (mV)	400	600	800	900	1000	1200				

Note to Table 1-22:

(1) This setting is required for compliance with the PCIe protocol.

Symbol	Parameter	Min	Тур	Max	Unit
t _{dlock}	Time required to lock dynamically (after switchover, reconfiguring any non-post-scale counters/delays or areset is deasserted)	_	_	1	ms
t _{outjitter_period_dedclk} (6)	Dedicated clock output period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	—	30	mUI
t _{outjitter_ccj_dedclk} (6)	Dedicated clock output cycle-to-cycle jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	300	ps
	F _{OUT} < 100 MHz	_	_	30	mUI
t _{outjitter_period_10} (6)	Regular I/O period jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	650	ps
	F _{OUT} < 100 MHz	—	_	75	mUI
t _{outjitter_ccj_io} <i>(6)</i>	Regular I/O cycle-to-cycle jitter $F_{OUT} \ge 100 \text{ MHz}$	_	_	650	ps
	F _{OUT} < 100 MHz	—	_	75	mUI
t _{PLL_PSERR}	Accuracy of PLL phase shift	—	_	±50	ps
t _{ARESET}	Minimum pulse width on areset signal.	10	_		ns
t _{CONFIGPLL}	Time required to reconfigure scan chains for PLLs	_	3.5 (7)		SCANCLK cycles
f _{scanclk}	scanclk frequency	—	—	100	MHz
t _{casc_outjitter_period_dedclk}	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \ge 100 \text{ MHz}$)	_	_	425	ps
(8), (9)	Period jitter for dedicated clock output in cascaded PLLs ($F_{OUT} < 100 \text{ MHz}$)	_		42.5	mUI

Table 1-25.	PLL Specifications	s for Cyclone IV Devices ^{(1),}	⁽²⁾ (Part 2 of 2)
-------------	--------------------	--	------------------------------

Notes to Table 1-25:

- (1) This table is applicable for general purpose PLLs and multipurpose PLLs.
- (2) You must connect $V_{\text{CCD_PLL}}$ to V_{CCINT} through the decoupling capacitor and ferrite bead.
- (3) This parameter is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.
- (4) The V_{C0} frequency reported by the Quartus II software in the PLL Summary section of the compilation report takes into consideration the V_{C0} post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VC0} specification.
- (5) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source that is less than 200 ps.
- (6) Peak-to-peak jitter with a probability level of 10⁻¹² (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL when an input jitter of 30 ps is applied.
- (7) With 100-MHz scanclk frequency.
- (8) The cascaded PLLs specification is applicable only with the following conditions:
 - $\blacksquare \quad Upstream \ PLL {----}0.59 \ MHz \leq Upstream \ PLL \ bandwidth < 1 \ MHz$
 - Downstream PLL—Downstream PLL bandwidth > 2 MHz
- (9) PLL cascading is not supported for transceiver applications.

Table 1–29 lists the active configuration mode specifications for Cyclone IV devices.

Programming Mode	DCLK Range	Typical DCLK	Unit
Active Parallel (AP) ⁽¹⁾	20 to 40	33	MHz
Active Serial (AS)	20 to 40	33	MHz

Table 1–29. Active Configuration Mode Specifications for Cyclone IV Devices

Note to Table 1-29:

(1) AP configuration mode is only supported for Cyclone IV E devices.

Table 1-30 lists the JTAG timing parameters and values for Cyclone IV devices.

Table 1–30. JTAG Timing Parameters for Cyclone IV Devices (1)

Symbol	Parameter	Min	Max	Unit
t _{JCP}	TCK clock period	40	—	ns
t _{JCH}	TCK clock high time	19	_	ns
t _{JCL}	TCK clock low time	19	_	ns
t _{JPSU_TDI}	JTAG port setup time for TDI	1	_	ns
t _{JPSU_TMS}	JTAG port setup time for TMS	3	_	ns
t _{JPH}	JTAG port hold time	10	_	ns
t _{JPC0}	JTAG port clock to output ^{(2), (3)}	—	15	ns
t _{JPZX}	JTAG port high impedance to valid output ^{(2), (3)}	—	15	ns
t _{JPXZ}	JTAG port valid output to high impedance ^{(2), (3)}	—	15	ns
t _{JSSU}	Capture register setup time	5	_	ns
t _{JSH}	Capture register hold time	10	_	ns
t _{JSC0}	Update register clock to output	_	25	ns
t _{JSZX}	Update register high impedance to valid output	_	25	ns
t _{JSXZ}	Update register valid output to high impedance		25	ns

Notes to Table 1-30:

(1) For more information about JTAG waveforms, refer to "JTAG Waveform" in "Glossary" on page 1–37.

- (2) The specification is shown for 3.3-, 3.0-, and 2.5-V LVTTL/LVCMOS operation of JTAG pins. For 1.8-V LVTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 16 ns.
- (3) For EP4CGX22, EP4CGX30 (F324 and smaller package), EP4CGX110, and EP4CGX150 devices, the output time specification for 3.3-, 3.0-, and 2.5-V LVTTL/LVCMOS operation of JTAG pins is 16 ns. For 1.8-V LVTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 18 ns.

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/Os using the SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speeds. I/Os using general-purpose I/O standards such as 3.3-, 3.0-, 2.5-, 1.8-, or 1.5-LVTTL/LVCMOS are capable of a typical 200 MHz interfacing frequency with a 10 pF load.

- ***** For more information about the supported maximum clock rate, device and pin planning, IP implementation, and device termination, refer to *Section III: System Performance Specifications* of the *External Memory Interfaces Handbook*.
- Actual achievable frequency depends on design- and system-specific factors. Perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specifications

Table 1–31 through Table 1–36 list the high-speed I/O timing for Cyclone IV devices. For definitions of high-speed timing specifications, refer to "Glossary" on page 1–37.

Table 1–31. RSDS Transmitter Timing Specifications for Cyclone IV Devices (1), (2), (4) (Part 1 of 2)

0 milest			C6			C7, I	7		C8, A	7	C8L, 18L					Unit	
Symbol	Modes	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UNIT
	×10	5		180	5		155.5	5		155.5	5		155.5	5		132.5	MHz
	×8	5		180	5		155.5	5		155.5	5		155.5	5		132.5	MHz
f _{HSCLK} (input clock	×7	5	_	180	5	—	155.5	5	_	155.5	5	_	155.5	5	_	132.5	MHz
(input clock frequency)	×4	5	_	180	5	—	155.5	5	_	155.5	5	_	155.5	5	_	132.5	MHz
1 37	×2	5		180	5		155.5	5		155.5	5		155.5	5		132.5	MHz
	×1	5	_	360	5		311	5	_	311	5	_	311	5		265	MHz
	×10	100	_	360	100		311	100	_	311	100	_	311	100	_	265	Mbps
	×8	80		360	80		311	80		311	80		311	80		265	Mbps
Device operation in	×7	70		360	70	—	311	70		311	70		311	70	—	265	Mbps
Mbps	×4	40		360	40	—	311	40		311	40		311	40	—	265	Mbps
	×2	20	_	360	20	—	311	20	_	311	20	—	311	20	—	265	Mbps
	×1	10		360	10	—	311	10		311	10		311	10	—	265	Mbps
t _{DUTY}	—	45		55	45		55	45		55	45		55	45		55	%
Transmitter channel-to- channel skew (TCCS)	_	_		200	_	_	200	_	_	200	_		200	_	_	200	ps
Output jitter (peak to peak)	—	_	_	500	_	_	500	_	_	550	_	_	600	_	_	700	ps
t _{RISE}	20 - 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500		_	500		ps
t _{FALL}	20 – 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500		ps

Symbol	Symbol	Modes		C6			C7, 17			C8, A7	7		C8L, 18	L		C9L		Unit
	wodes	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit	
t _{LOCK} (2)	_	—		1		—	1	_		1	—		1		—	1	ms	

Table 1–32. Emulated RSDS_E	1R Transmitter Timing	Specifications for C	vclone IV Devices ^{(1), (3)}	(Part 2 of 2)
		• • • • • • • • • • • • • • • • •		(

Notes to Table 1-32:

(1) Emulated RSDS_E_1R transmitter is supported at the output pin of all I/O Banks of Cyclone IV E devices and I/O Banks 3, 4, 5, 6, 7, 8, and 9 of Cyclone IV GX devices.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Modes		C6			C7, 17	7		C8, A	7		C8L, I	8L			Unit	
Symbol	woues	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIL
	×10	5	_	200	5	—	155.5	5	—	155.5	5	—	155.5	5	_	132.5	MHz
	×8	5	_	200	5	_	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
f _{HSCLK} (input clock	×7	5	_	200	5	_	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
frequency)	×4	5	_	200	5	—	155.5	5	—	155.5	5		155.5	5		132.5	MHz
,	×2	5	_	200	5	_	155.5	5	—	155.5	5	_	155.5	5	_	132.5	MHz
	×1	5	_	400	5	_	311	5	—	311	5	_	311	5	_	265	MHz
	×10	100	_	400	100	_	311	100	—	311	100		311	100		265	Mbps
	×8	80	_	400	80	_	311	80	—	311	80	_	311	80	_	265	Mbps
Device operation in	×7	70	_	400	70	—	311	70	—	311	70	_	311	70	—	265	Mbps
Mbps	×4	40	—	400	40	—	311	40	—	311	40	_	311	40	—	265	Mbps
	×2	20		400	20		311	20	_	311	20		311	20	_	265	Mbps
	×1	10	_	400	10	—	311	10		311	10	_	311	10		265	Mbps
t _{DUTY}	—	45	_	55	45	_	55	45	—	55	45		55	45		55	%
TCCS	—	_	_	200	_	_	200	_	—	200	_	_	200	_	_	200	ps
Output jitter (peak to peak)	_	_	_	500	_	_	500	_		550	_	_	600		_	700	ps
t _{RISE}	20 - 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500	_	ps
t _{FALL}	20 - 80%, C _{LOAD} = 5 pF	_	500	_	_	500	_	_	500	_	_	500	_	_	500	_	ps
t _{LOCK} (3)				1			1			1			1			1	ms

Table 1–33. Mini-LVDS Transmitter Timing Specifications for Cyclone IV Devices (1), (2), (4)

Notes to Table 1-33:

(1) Applicable for true and emulated mini-LVDS transmitter.

(2) Cyclone IV E—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated mini-LVDS transmitter is supported at the output pin of all I/O banks.
Cyclone IV GY—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of Row I/O Banks 5.

Cyclone IV GX—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Symbol	Madaa	C	6	C7,	, 17	C8,	A7	C8L,	, 18L	C	9L	Unit
Symbol	Modes	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
t _{DUTY}	—	45	55	45	55	45	55	45	55	45	55	%
TCCS	—	_	200	—	200	_	200	_	200	_	200	ps
Output jitter (peak to peak)	_		500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	_		1	_	1		1		1	_	1	ms

Table 1–35. Emulated LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 2 of 2)

Notes to Table 1-35:

(1) Cyclone IV E—emulated LVDS transmitter is supported at the output pin of all I/O Banks.

Cyclone IV GX—emulated LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Gumbal	Madaa	C	6	C7,	, 17	C8,	A7	C8L	, 18L	C)L	11
Symbol	Modes	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
	×10	10	437.5	10	370	10	320	10	320	10	250	MHz
	×8	10	437.5	10	370	10	320	10	320	10	250	MHz
f _{HSCLK} (input clock	×7	10	437.5	10	370	10	320	10	320	10	250	MHz
frequency)	×4	10	437.5	10	370	10	320	10	320	10	250	MHz
, ,,	×2	10	437.5	10	370	10	320	10	320	10	250	MHz
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	MHz
	×10	100	875	100	740	100	640	100	640	100	500	Mbps
	×8	80	875	80	740	80	640	80	640	80	500	Mbps
HSIODR	×7	70	875	70	740	70	640	70	640	70	500	Mbps
HOIDDN	×4	40	875	40	740	40	640	40	640	40	500	Mbps
	×2	20	875	20	740	20	640	20	640	20	500	Mbps
	×1	10	437.5	10	402.5	10	402.5	10	362	10	265	Mbps
SW	—	_	400	_	400	_	400	_	550	—	640	ps
Input jitter tolerance	_	_	500	_	500	_	550	_	600	_	700	ps
t _{LOCK} (2)	—	—	1	—	1	—	1	—	1	—	1	ms

Table 1–36. LVDS Receiver Timing Specifications for Cyclone IV Devices (1), (3)

Notes to Table 1-36:

(1) Cyclone IV E—LVDS receiver is supported at all I/O Banks.

Cyclone IV GX—LVDS receiver is supported at I/O Banks 3, 4, 5, 6, 7, 8, and 9.

(2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

External Memory Interface Specifications

The external memory interfaces for Cyclone IV devices are auto-calibrating and easy to implement.

• For more information about the supported maximum clock rate, device and pin planning, IP implementation, and device termination, refer to *Section III: System Performance Specifications* of the *External Memory Interface Handbook*.

Table 1–37 lists the memory output clock jitter specifications for Cyclone IV devices.

Table 1–37. Memory Output Clock Jitter Specifications for Cyclone IV Devices (1), (2)

Parameter	Symbol	Min	Max	Unit
Clock period jitter	t _{JIT(per)}	-125	125	ps
Cycle-to-cycle period jitter	t _{JIT(cc)}	-200	200	ps
Duty cycle jitter	t _{JIT(duty)}	-150	150	ps

Notes to Table 1-37:

(1) Memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2 standard.

(2) The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a global clock (GCLK) network.

Duty Cycle Distortion Specifications

Table 1–38 lists the worst case duty cycle distortion for Cyclone IV devices.

Table 1–38. Duty Cycle Distortion on Cyclone IV Devices I/O Pins (1), (2), (3)

Symbol	C		C7, I7		C8, I8	BL, A7	C	Unit	
Symbol	Min	Max	Min	Max	Min	Max	Min	Max	UIIIL
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Notes to Table 1-38:

(1) The duty cycle distortion specification applies to clock outputs from the PLLs, global clock tree, and IOE driving the dedicated and general purpose I/O pins.

(2) Cyclone IV devices meet the specified duty cycle distortion at the maximum output toggle rate for each combination of I/O standard and current strength.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

OCT Calibration Timing Specification

Table 1–39 lists the duration of calibration for series OCT with calibration at device power-up for Cyclone IV devices.

Table 1–39. Timing Specification for Series OCT with Calibration at Device Power-Up for Cyclone IV Devices $^{(1)}$

Symbol	Description	Maximum	Units	
t _{octcal}	Duration of series OCT with calibration at device power-up	20	μs	

Note to Table 1-39:

(1) OCT calibration takes place after device configuration and before entering user mode.

Table 1–42 and Table 1–43 list the IOE programmable delay for Cyclone IV E 1.2 V core voltage devices.

		Number	Min Offset	Max Offset									
Parameter	Paths Affected	of		Fact Lorner				SI	ow Corn	ow Corner			
		Setting		C6	17	A7	C6	C7	C8	17	A7		
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.211	1.211	2.177	2.340	2.433	2.388	2.508	ns	
Input delay from pin to input register	Pad to I/O input register	8	0	1.307	1.203	1.203	2.19	2.387	2.540	2.430	2.545	ns	
Delay from output register to output pin	I/O output register to pad	2	0	0.437	0.402	0.402	0.747	0.820	0.880	0.834	0.873	ns	
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.693	0.665	0.665	1.200	1.379	1.532	1.393	1.441	ns	

Notes to Table 1-42:

(1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

	Paths Affected	Number of Setting	Min Offset	Max Offset								
Parameter				Fast Corner			Slow Corner					Unit
				C6	17	A7	C6	C7	C8	17	A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.209	1.209	2.201	2.386	2.510	2.429	2.548	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.207	1.207	2.202	2.402	2.558	2.447	2.557	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.458	0.419	0.419	0.783	0.861	0.924	0.875	0.915	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.686	0.657	0.657	1.185	1.360	1.506	1.376	1.422	ns

Table 1–43. IOE Programmable Delay on Row Pins for Cyclone IV E 1.2 V Core Voltage Devices (1), (2)

Notes to Table 1-43:

(1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

I/O Timing

Use the following methods to determine I/O timing:

- the Excel-based I/O Timing
- the Quartus II timing analyzer

The Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get a timing budget estimation as part of the link timing analysis. The Quartus II timing analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after place-and-route is complete.

The Excel-based I/O Timing spreadsheet is downloadable from Cyclone IV Devices Literature website.

Glossary

Table 1–46 lists the glossary for this chapter.

Letter	Term	Definitions				
Α	—	—				
В	—	—				
C	—	—				
D	—					
E	—	_				
F	f _{HSCLK}	High-speed I/O block: High-speed receiver/transmitter input and output clock frequency.				
G	GCLK	Input pin directly to Global Clock network.				
u	GCLK PLL	Input pin to Global Clock network through the PLL.				
Н	HSIODR	High-speed I/O block: Maximum/minimum LVDS data transfer rate (HSIODR = 1/TUI).				
I	Input Waveforms for the SSTL Differential I/O Standard	Vswing Vswing V _{IH} V _{REF} V _{IL}				

Table 1-46. Glossary (Part 1 of 5)

Letter	Term	Term Definitions					
	t _C	High-speed receiver and transmitter input and output clock period.					
	Channel-to- channel-skew (TCCS)	High-speed I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.					
	t _{cin}	Delay from the clock pad to the I/O input register.					
	t _{co}	Delay from the clock pad to the I/O output.					
	t _{cout}	Delay from the clock pad to the I/O output register.					
	t _{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.					
	t _{FALL}	Signal high-to-low transition time (80–20%).					
	t _H	Input register hold time.					
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(\text{Receiver Input Clock Frequency Multiplication Factor}) = t_c/w$).					
	t _{INJITTER}	Period jitter on the PLL clock input.					
	t _{outjitter_dedclk}	Period jitter on the dedicated clock output driven by a PLL.					
	t _{outjitter_i0}	Period jitter on the general purpose I/O driven by a PLL.					
	t _{pllcin}	Delay from the PLL inclk pad to the I/O input register.					
т	t _{plicout}	Delay from the PLL inclk pad to the I/O output register.					
	Transmitter Output Waveform	Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards: Single-Ended Waveform V_{OD} $V_{$					
	t _{RISE}	Signal low-to-high transition time (20–80%).					
	t _{SU}	Input register setup time.					
U	— —	_					

Table 1–46. Glossary (Part 4 of 5)

Table 1-46. Glossary (Part 5 of 5)

Letter	Term	Definitions					
	V _{CM(DC)}	DC common mode input voltage.					
	V _{DIF(AC)}	AC differential input voltage: The minimum AC input differential voltage required for switching.					
	V _{DIF(DC)}	DC differential input voltage: The minimum DC input differential voltage required for switching.					
	V _{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.					
	V _{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.					
	V _{IH}	Voltage input high: The minimum positive voltage applied to the input that is accepted by the device as a logic high.					
	V _{IH(AC)}	High-level AC input voltage.					
	V _{IH(DC)}	High-level DC input voltage.					
	V _{IL}	Voltage input low: The maximum positive voltage applied to the input that is accepted by the device as a logic low.					
	V _{IL (AC)}	Low-level AC input voltage.					
	V _{IL (DC)}	Low-level DC input voltage.					
	V _{IN}	DC input voltage.					
	V _{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.					
V	V _{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter. $V_{0D} = V_{0H} - V_{0L}$.					
	V _{OH}	Voltage output high: The maximum positive voltage from an output that the device considers is accepted as the minimum positive high level.					
	V _{OL}	Voltage output low: The maximum positive voltage from an output that the device considers is accepted as the maximum positive low level.					
	V _{os}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.					
	V _{OX (AC)}	AC differential output cross point voltage: the voltage at which the differential output signals must cross.					
	V _{REF}	Reference voltage for the SSTL and HSTL I/O standards.					
	V _{REF (AC)}	AC input reference voltage for the SSTL and HSTL I/O standards. $V_{REF(AC)} = V_{REF(DC)} + noise$. The peak-to-peak AC noise on V_{REF} must not exceed 2% of $V_{REF(DC)}$.					
	V _{REF (DC)}	DC input reference voltage for the SSTL and HSTL I/O standards.					
	V _{SWING (AC)}	AC differential input voltage: AC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.					
	V _{SWING (DC)}	DC differential input voltage: DC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.					
	V _{TT}	Termination voltage for the SSTL and HSTL I/O standards.					
	V _{X (AC)}	AC differential input cross point voltage: The voltage at which the differential input signals must cross.					
W	—	_					
X	—	—					
Y	—	_					
Z	—	_					

Document Revision History

Table 1–47 lists the revision history for this chapter.

Date	Version	Changes		
March 2016	2.0	Updated note (5) in Table 1–21 to remove support for the N148 package.		
Ostobor 2014	1.9	Updated maximum value for V _{CCD_PLL} in Table 1–1.		
October 2014		Removed extended temperature note in Table 1–3.		
December 2013	1.8	Updated Table 1–21 by adding Note (15).		
May 2013	1.7	Updated Table 1–15 by adding Note (4).		
	1.6	■ Updated the maximum value for V _I , V _{CCD_PLL} , V _{CCI0} , V _{CC_CLKIN} , V _{CCH_GXB} , and V _{CCA_GXB} Table 1–1.		
		■ Updated Table 1–11 and Table 1–22.		
October 2012		 Updated Table 1–21 to include peak-to-peak differential input voltage for the Cyclone IV GX transceiver input reference clock. 		
		■ Updated Table 1–29 to include the typical DCLK value.		
		 Updated the minimum f_{HSCLK} value in Table 1–31, Table 1–32, Table 1–33, Table 1–34, and Table 1–35. 		
	1.5	 Updated "Maximum Allowed Overshoot or Undershoot Voltage", "Operating Conditions", and "PLL Specifications" sections. 		
November 2011		 Updated Table 1–2, Table 1–3, Table 1–4, Table 1–5, Table 1–8, Table 1–9, Table 1–15, Table 1–18, Table 1–19, and Table 1–21. 		
		■ Updated Figure 1–1.		
	1.4	 Updated for the Quartus II software version 10.1 release. 		
December 2010		■ Updated Table 1–21 and Table 1–25.		
		 Minor text edits. 		
		Updated for the Quartus II software version 10.0 release:		
	1.3	■ Updated Table 1–3, Table 1–4, Table 1–21, Table 1–25, Table 1–28, Table 1–30, Table 1–40, Table 1–41, Table 1–42, Table 1–43, Table 1–44, and Table 1–45.		
July 2010		■ Updated Figure 1–2 and Figure 1–3.		
		 Removed SW Requirement and TCCS for Cyclone IV Devices tables. 		
		 Minor text edits. 		
	1.2	Updated to include automotive devices:		
		 Updated the "Operating Conditions" and "PLL Specifications" sections. 		
March 2010		 Updated Table 1–1, Table 1–8, Table 1–9, Table 1–21, Table 1–26, Table 1–27, Table 1–31, Table 1–32, Table 1–33, Table 1–34, Table 1–35, Table 1–36, Table 1–37, Table 1–38, Table 1–40, Table 1–42, and Table 1–43. 		
		 Added Table 1–5 to include ESD for Cyclone IV devices GPIOs and HSSI I/Os. 		
		 Added Table 1–44 and Table 1–45 to include IOE programmable delay for Cyclone IV E 1.2 V core voltage devices. 		
		 Minor text edits. 		

Table 1–47. Document Revision History

Date	Version	Changes
February 2010	1.1	 Updated Table 1–3 through Table 1–44 to include information for Cyclone IV E devices and Cyclone IV GX devices for Quartus II software version 9.1 SP1 release. Minor text edits.
November 2009	1.0	Initial release.